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Date: February 20, 2003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael Schittenhelm
Applic. No. : 09/992,290
Filed : November 16, 2001
Title : Method of Calibrating a Test System for
Semiconductor Components, and Test Substrate
Examiner : Tung X. Nguyen
Group Art Unit : 2829

A M E N D M E N T

Hon. Commissioner of Patents and Trademarks,
Washington, D. C. 20231

S i r :

Responsive to the Office action dated November 20, 2002 kindly
amend the above-identified application as follows:

In the Claims:

a' Claim 1(amended). A calibration method for a test system
wherein semiconductor components are tested by making contact
with a component to be tested via a probe card, the method
which comprises:

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